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| STATEMENT BY APPLICANT |
| (Not for submission under 37 CEP 1 99) |

| Application Number | | 10644718 | | | |
|------------------------|-------|-----------------------|---|--|--|
| Filing Date | | 2003-08-20 | | | |
| First Named Inventor | Yi-Hs | sun Wu et al. | | | |
| Art Unit | | 2836 | | | |
| Examiner Name | Dann | y Nguyen | _ | | |
| Attorney Docket Number | | TSMC2003-246/1085-191 | | | |

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| 1 | JIAN-HSING LEE, J.R. SHIH, Y.H. WU, T.C. ONG, "The Failure Mechanism Of High Voltage Tolerance IO Buffer Under ESD," IEEE 03CH37400. 41st Annual International Reliability Physics Symposium, Dallas, Texas, 2003 (Pages 269-276) © 2003 IEEE. | | | | | | |
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